

Sheet 1 of 3

PTO-1449 (Modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. 219.003-US	SERIAL NUMBER 09/865,528
	APPLICANT(S) Yamada	
	FILING DATE May 29, 2001	GROUP ART UNIT 2829

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
V	5,888,019					

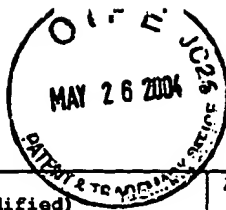
FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO
VN	63-009807	1/1988	Japan			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

VN	"An In-Line Contact and Via Hole Inspection Method Using Electron Beam Compensation Current", Yamada et al., IEEE 1999, Doc. No. 0-7803-5413-3/99/, available from http://www.fabsol.com/us/images/library/21.pdf

EXAMINER <i>AS</i> <i>anh Nguyen</i>	DATE CONSIDERED <i>08/05/04</i>
EXAMINER: Initial citation if reference was considered. Draw line through citation if not in conformance to MPEP 609 and not considered. Include copy of this form with next communication to applicant.	



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EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
VN	5,989,919	11/1999	Aoki			
VN	6,466,315	10/2002	Karpol et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO

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